

PATENT  
Attorney Docket No.: AMS-018  
(122242/169509)

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

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|----------------|---------------------------------|------------------|--------------------|
| APPLICANT(S):  | Maznev                          | CONFIRMATION NO. | 8648               |
| SERIAL NUMBER: | 10/553,146                      | GROUP NO.:       | 2886               |
| FILING DATE:   | October 25, 2006                | EXAMINER:        | LaPage, Michael P. |
| TITLE:         | METHOD FOR MEASURING THIN FILMS |                  |                    |

**Terminal Disclaimer**

I, Chris Moore, residing at 849 Boston Post Rd, Marlboro, NJ, state that I am a representative authorized to sign on behalf of Advanced Metrology Systems, LLC, identified below as the assignee of the entire right, title and interest in and to the above-identified patent application, U.S. Serial No. 10/553,146. I have reviewed all the evidentiary documents accompanying or referred to in the instant Terminal Disclaimer and certify that, to the best of my knowledge and belief, title to the above-identified application is in the name of Advanced Metrology Systems, LLC.

Advanced Metrology Systems, LLC, of 12 Michigan Drive, Natick, Massachusetts 01760, is the assignee of the entire right, title and interest in and to the above-identified application, 10/553,146, by virtue of assignments showing a chain of title from the inventor(s) to the current assignee, as follows: From: Alexei Maznev, To: Advanced Metrology Systems, LLC, recorded in the United States Patent and Trademark Office at Reel 019683, Frame 0650.

Advanced Metrology Systems, LLC, of 12 Michigan Drive, Natick, Massachusetts 01760, is also the assignee of the entire right, title and interest in and to U.S. Patent No. 7,365,864, by virtue of assignments showing a chain of title from the inventor(s) to the current assignee, as follows: From: Michael Gostein and Alex Maznev, To: Koninklijke Philips Electronics N.V., recorded in the United States Patent and Trademark Office at Reel 017707, Frame 0850; and From: Koninklijke Philips Electronics N.V., To: Advanced Metrology Systems LLC, recorded in the United States Patent and Trademark Office at Reel 018585, Frame 0192.

Advanced Metrology Systems, LLC, hereby waives and disclaims the terminal part of any patent granted on the above-identified application, U.S. Serial No. 10/553,146, which would extend beyond the full statutory term of U.S. Patent No. 7,365,864, which issued from U.S. Serial No. 10/547,637 on April 29, 2008, and hereby agrees that any patent so granted on U.S. Serial No. 10/553,146 shall be enforceable only for and during such period that the patent is commonly owned with U.S. Patent No. 7,365,864. This agreement runs with any patent granted on the instant application and is binding upon the Assignee, its successors or assigns.

Advanced Metrology Systems, LLC, does not disclaim any terminal part of the term of any patent granted on the instant application , U.S. Serial No. 10/553,146, prior to the expiration date of the full statutory term of U.S. Patent No. 7,365,864 in the event that U.S. Patent No. 7,365,864 expires for failure to pay a maintenance fee, is held unenforceable, is found invalid by a court of competent jurisdiction, is statutorily disclaimed in whole or terminally disclaimed under 37 C.F.R. 1.321(a), has all claims canceled by a re-examination certificate, is reissued, or is otherwise terminated prior to expiration of its statutory term as presently shortened by any terminal disclaimer.

I hereby declare that all statements made herein of my own knowledge are true and that all statements made on information and belief are believed to be true; and further that these statements are made in the knowledge that willful false statements and the like so made are punishable by fine or imprisonment, or both, under Section 1001 of Title 18 of the United States Code and that such willful false statements may jeopardize the validity of the application or any patent issued thereon.

Advanced Metrology Systems, LLC

By CJ Mullan  
Name CJ Mullan  
Title CEO  
Date Sept 16/08